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# HARD ROCK SOLUTIONS SINCE 1927

On Stream Analyzer  
Systems for Mineral  
Processing

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The legend continues



# Introduction – Topics To Cover

- Why are OSA Systems required
- Sampling Systems required for Analyzers
- OSA System Overview
- What is XRF
- Radiation Safety
- The BOXA-II
- BOXA Benefits and Advantages
- Next Generation – BOXA-III
- Benefits of OSA Systems
- Some \$ Numbers



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# SHOULDER TO SHOULDER, SOLVING PROBLEMS

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# Why are OSA Systems required

- Mineral Processing industry processes ore
- Ore contains metals of interest (Cu, Zn, Ag, ...)
- Ore is upgrade to a concentrate in several stages, different circuits
- Each stage requires precise control to maximize a plants profitability (grade vs recovery)
- XRF measures element content (%Cu, %Zn, Ag ppm, ...) at different stages which is used for process control

# Why are analysis's required

- To control grade and recovery in a flotation circuit (Quality Control)
  - Grade – is the total element content in a sample ( feed, conc., tails)
  - Recovery - % of element recovered from the ore
- Some flotation control parameters
  - Assay based control can be implemented for plant optimization
  - Air addition and level controls on flotation cells
  - pH (acidity) of the slurry
  - Density of slurry
  - Amount of flotation chemicals, collectors, frothers, etc.



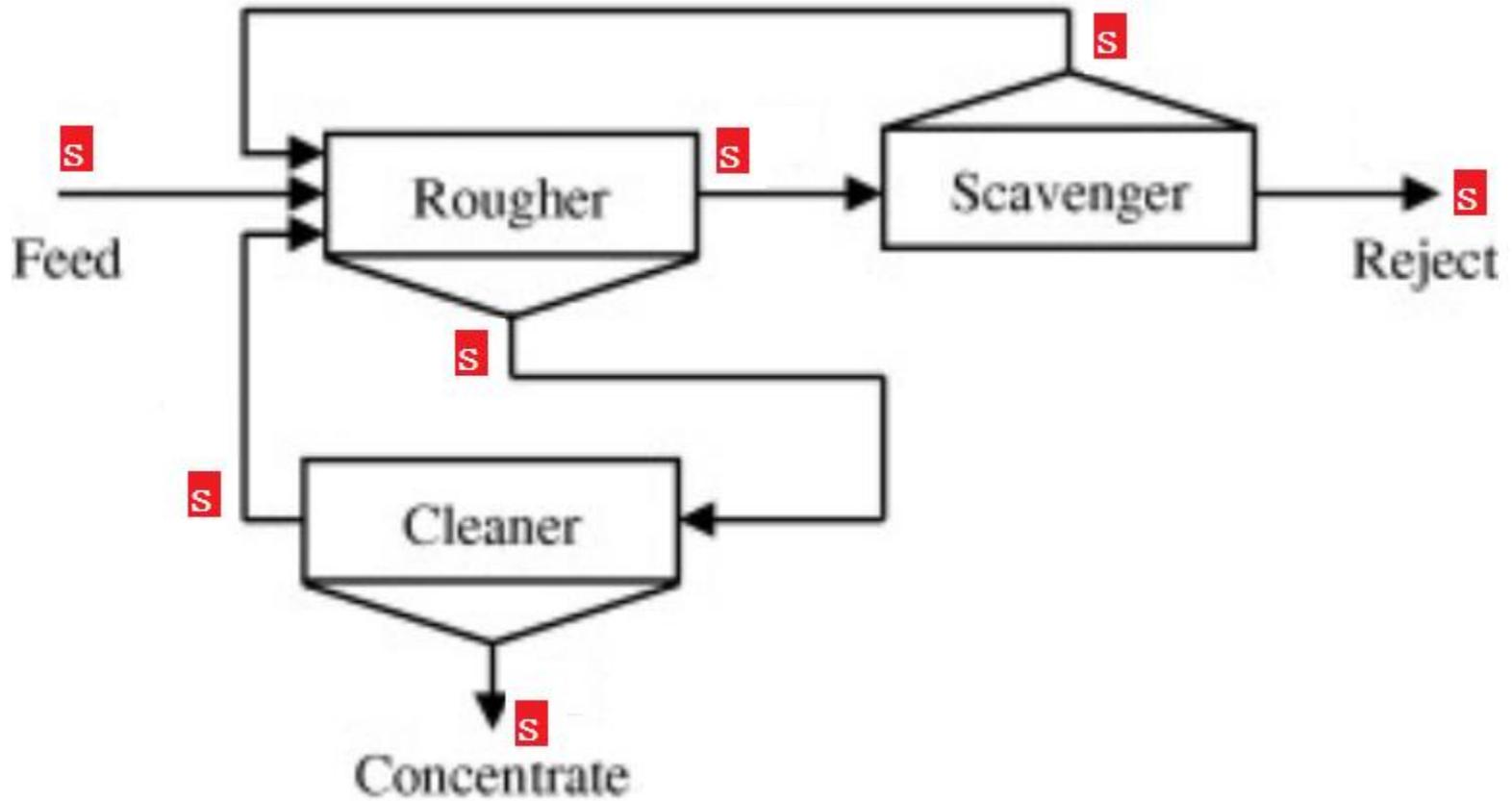
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# #1 IN SAMPLERS AND SAMPLING SYSTEMS

Sampling Systems  
required for Analyzers

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# Sampling Points



# Decide Type the of Samplers Required

- **Metallurgical Samplers**
  - Metallurgical reconciliation (Feed, Concentrate, Tails)
  - Requires samples that represent actual metal grades
  - Composite samples for laboratory analysis
- **Process Control Samplers**
  - Concentrate and tailings of each stage of the flotation process
  - Requires sampling to verify tendencies in the process
  - Important for maximizing metal recovery
  - Feed for On Stream (OSA) and Particle Size (PSM) Analyzers
  - Requires 8 to 12 m<sup>3</sup>/ hr continuous sample
- **IMPORTANT NOTE**
  - Metallurgical Samplers can be used for Process Control but NOT VISA VERSA

# Process Control Samplers -Bias Note

- **Process Control Samplers**

- These kinds of samplers contain a bias
- This bias changes over time due to changes in feed tonnages, particle size, densities, flow rates, pressure, etc.
- There can also be a constant bias plus a fluctuating bias

- **NOTE OF INTEREST**

- There was paper (Measurement Issues In Quality “Control”) presented by Brian Flintoff in 1992 at a CMP conference which stated: “Clearly, no bias can be accepted” as it pertains to OSA composition measurements
- If the sample feed to the OSA is biased, the result is biased!!!
- Not sure where the idea of PCS came from!

Allowing that the scenario described above is reasonable, and in particular the grade ( $\sim\pm 1\%$ ) and recovery ( $\sim\pm 0.5\%$ ) changes could be typical, it is possible to comment on the allowable noise in the OSA composition measurements. Clearly, no bias can be accepted (a most difficult condition to meet in view of matrix, particle size and pulp density effects).

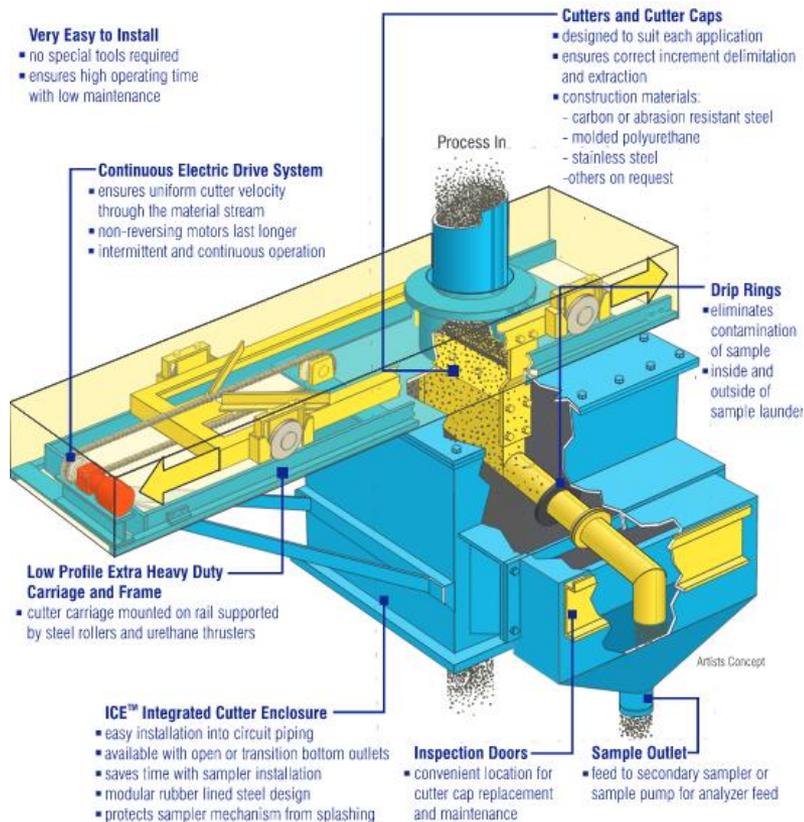
# Decide Type the of Samplers Required

- **Proper sampling engineering is required ensure samples are readily available to the OSA and are representative**
- **Sampling systems require periodic maintenance**
- **Sampler cutters can get plugged**
- **Sampling lines and pumps can sand out**
- **These factors affect the OSA and it's assay availability**

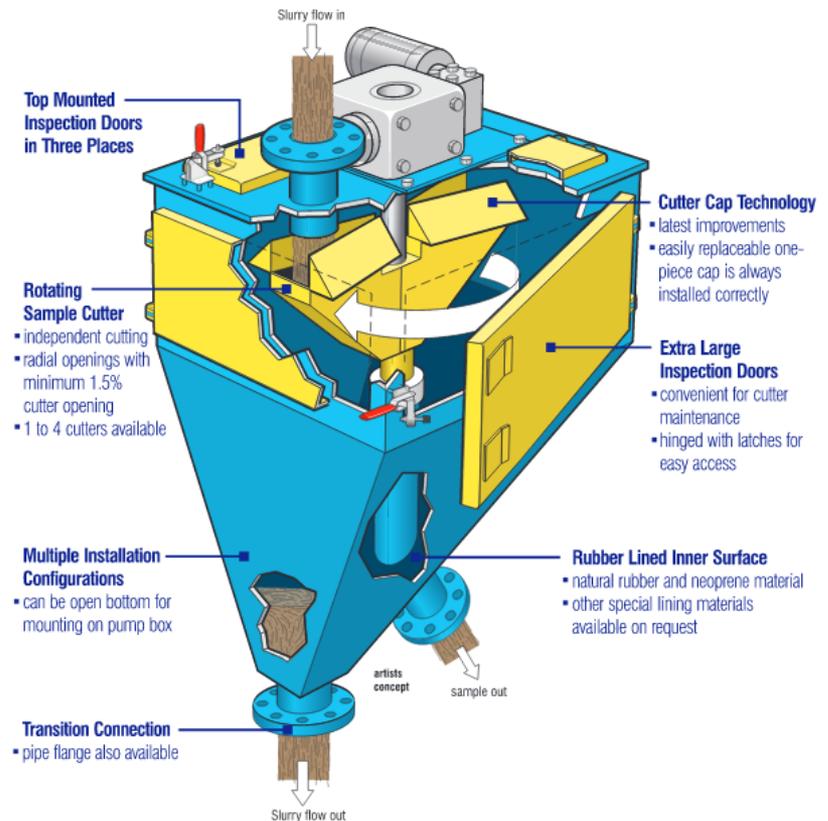
# Metallurgical Samplers

They cut completely across the stream

## Linear Sampler



## Rotary Vezin

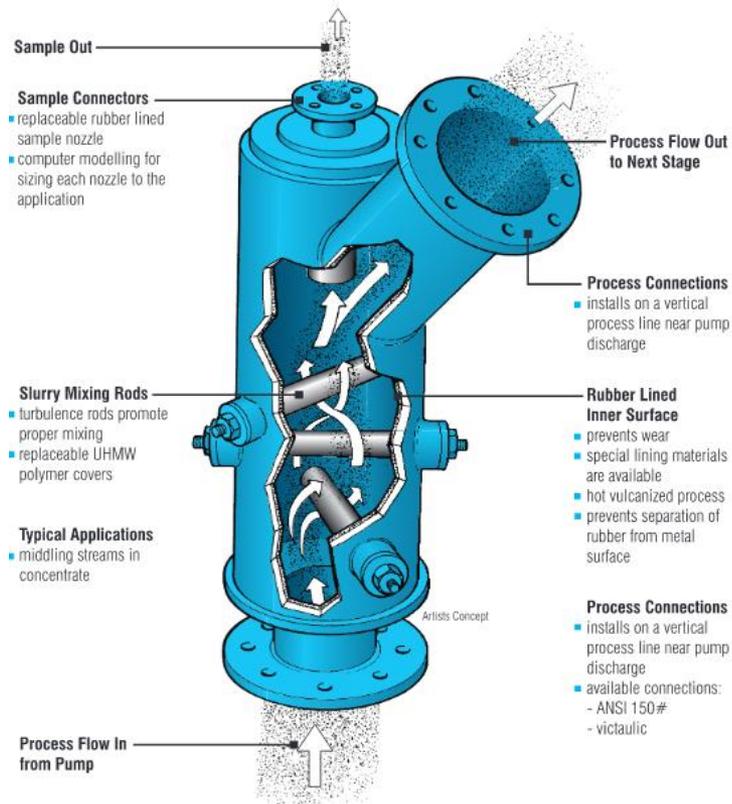


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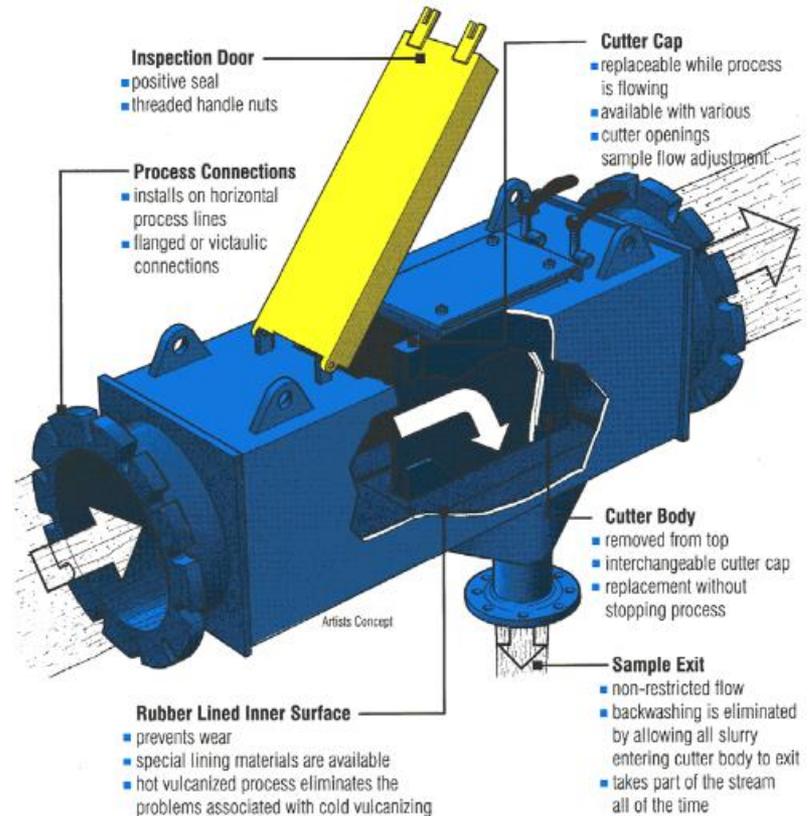
# Process Control Samplers

## Thief cutters

### Pressure Pipe Sampler



### Gravity Flow Sampler

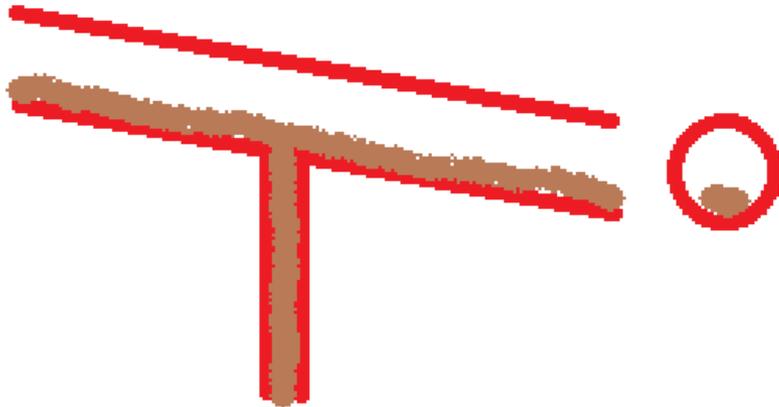


# Poor Samplers

## Home Made

- OSA analyzes what it is presented
- Biased samples produce biased assay results
- “Garbage In - Garbage Out”

Coarse Particle Bias





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# ANALYZING MINERALS FOR METAL CONTENT

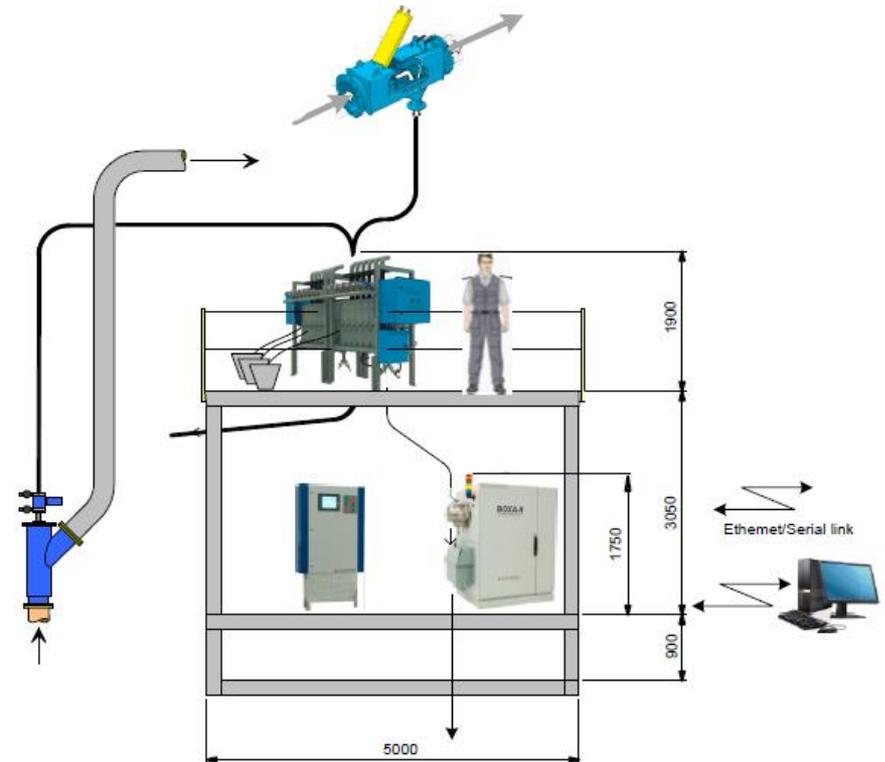
The BOXA System

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# OSA System Overview

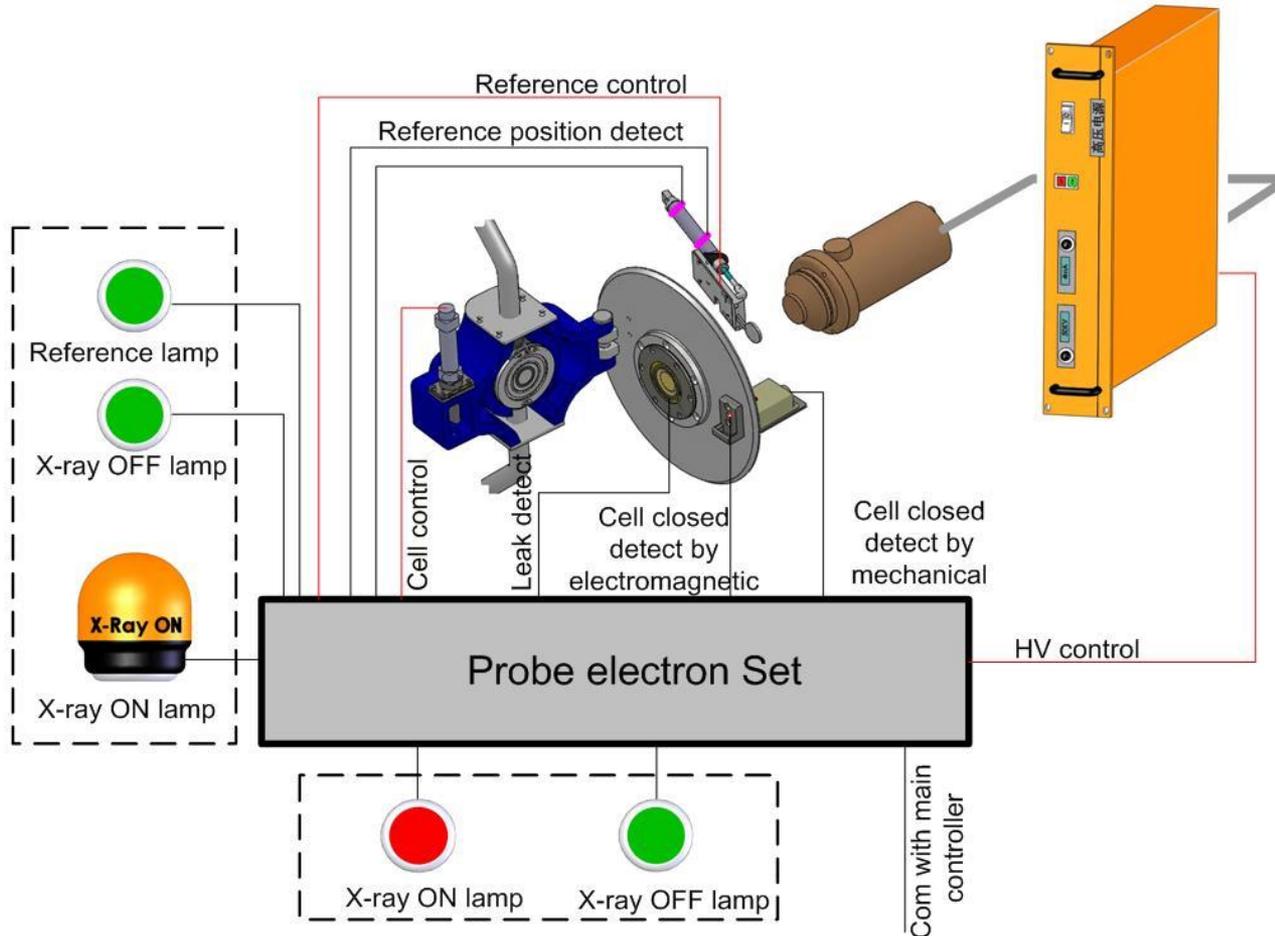
## Layout

- Samplers provide sample to the MXA's
- Return lines go back to the process
- MXA's direct a single sample to the probe to be measured
- CSA Sampler for calibration
- Assay results generated and sent to plant's DCS and displayed locally



# Interlocking safety

## Electromagnetic/Mechanical Visual Indication





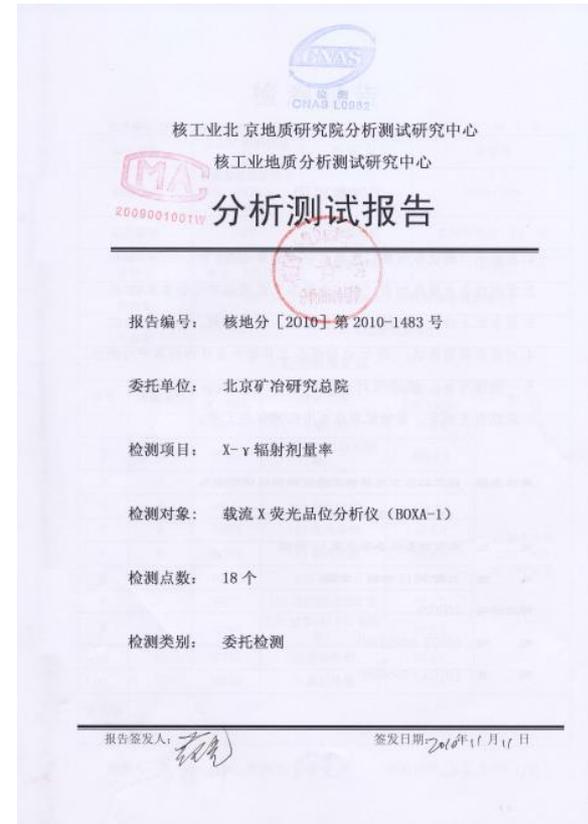
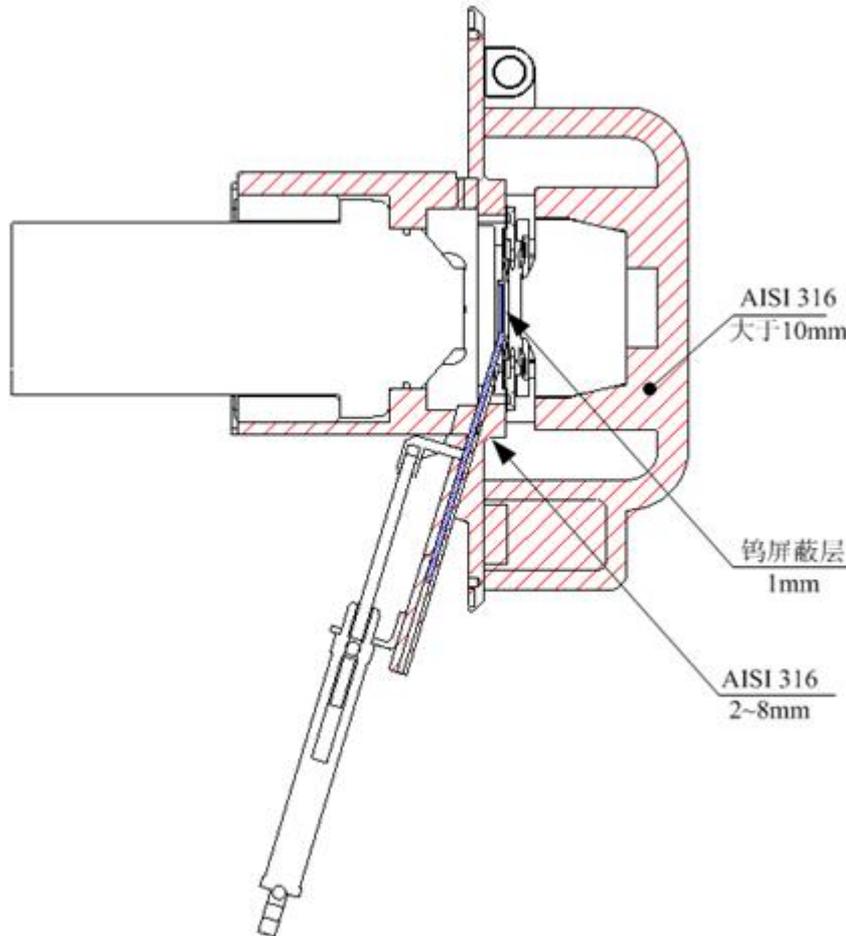
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# Radiation safety

Certified By



Radiation Safety  
Institute of Canada  
Institut de radioprotection du Canada



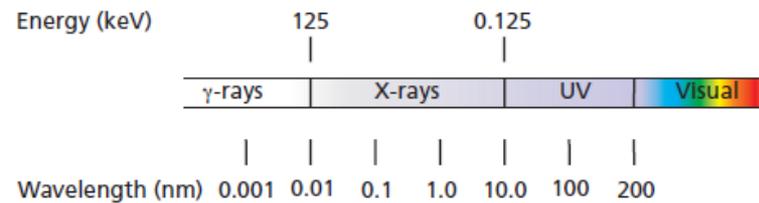
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# Electrical safety

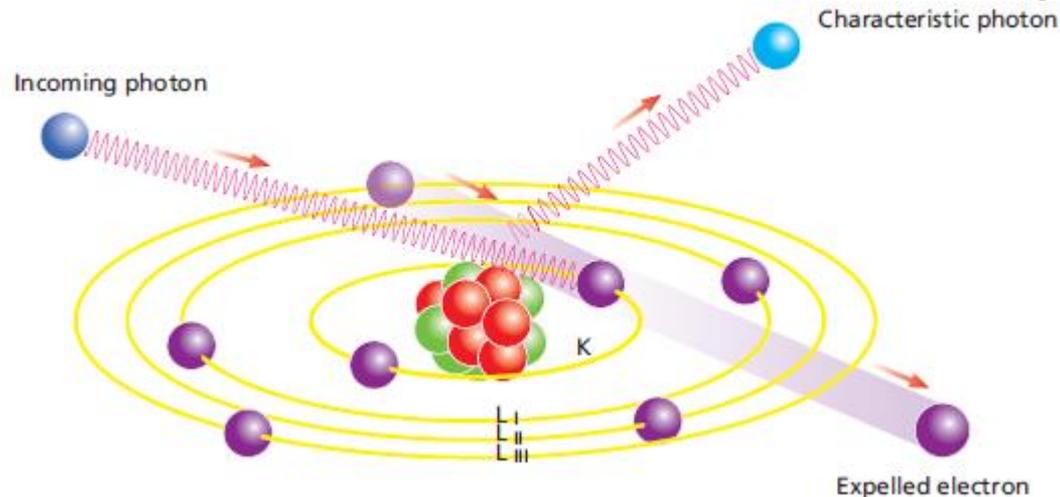
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| <b>Product:</b> On-stream x-ray fluorescence analyzer   |   |                              |  |
| <b>Brand Name:</b>   |   |                              |  |
| <b>Models:</b> BOXA-II  |   |                              |  |

# What is XRF

- X-Rays are part of the electromagnetic spectrum



- They interact with matter – ionizing.



# What is XRF

- The basic principles
  - Excite the characteristic x-rays of the elements
  - Measure their intensities
  - Calculate concentrations from intensities
- The energy (or wavelength) -> the element
  - Each element's (Cu, Zn,...) energy is unique
- The element intensity -> the assay of element
  - The higher the intensity, the greater the % of element
- Equations are derived to calculate assays from intensities. This is called calibration.



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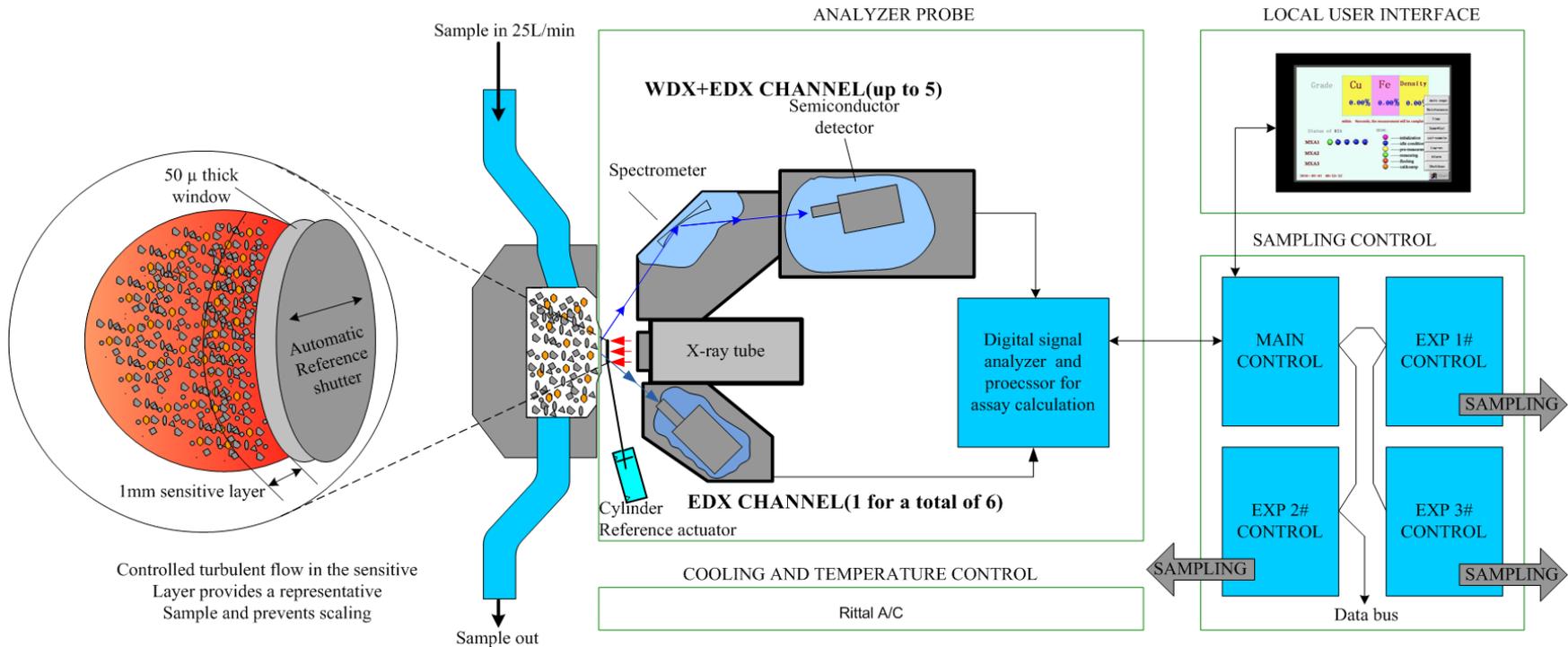
# Measuring Range

**Periodic table of elements**

|                      |          |          |          |          |          |          |          |          |          |          |          |          |           |           |           |           |                     |
|----------------------|----------|----------|----------|----------|----------|----------|----------|----------|----------|----------|----------|----------|-----------|-----------|-----------|-----------|---------------------|
| H<br>1               |          |          |          |          |          |          |          |          |          |          |          |          |           |           |           |           | He<br>2             |
| Li<br>3              | Be<br>4  |          |          |          |          |          |          |          |          |          |          | B<br>5   | C<br>6    | N<br>7    | O<br>8    | F<br>9    | Ne<br>10            |
| Na<br>11             | Mg<br>12 |          |          |          |          |          |          |          |          |          |          | Al<br>13 | Si<br>14  | P<br>15   | S<br>16   | Cl<br>17  | Ar<br>18            |
| K<br>19              | Ca<br>20 | Sc<br>21 | Ti<br>22 | V<br>23  | Cr<br>24 | Mn<br>25 | Fe<br>26 | Co<br>27 | Ni<br>28 | Cu<br>29 | Zn<br>30 | Ga<br>31 | Ge<br>32  | As<br>33  | Se<br>34  | Br<br>35  | Kr<br>36            |
| Rb<br>37             | Sr<br>38 | Y<br>39  | Zr<br>40 | Nb<br>41 | Mo<br>42 | Tc<br>43 | Ru<br>44 | Rh<br>45 | Pd<br>46 | Ag<br>47 | Cd<br>48 | In<br>49 | Sn<br>50  | Sb<br>51  | Te<br>52  | I<br>53   | Xe<br>54            |
| Cs<br>55             | Ba<br>56 | 57-71    | Hf<br>72 | Ta<br>73 | W<br>74  | Re<br>75 | Os<br>76 | Ir<br>77 | Pt<br>78 | Au<br>79 | Hg<br>80 | Tl<br>81 | Pb<br>82  | Bi<br>83  | Po<br>84  | At<br>85  | Rn<br>86            |
| Fr<br>87             | Ra<br>88 | Ac<br>89 | Th<br>90 | Pa<br>91 | U<br>92  | Np<br>93 | Pu<br>94 | Am<br>95 | Cm<br>96 | Bk<br>97 | Cf<br>98 | Es<br>99 | Fm<br>100 | Md<br>101 | No<br>102 | Lr<br>103 | Actinides<br>89-103 |
| Lanthanides<br>57-71 |          | La<br>57 | Ce<br>58 | Pr<br>59 | Nd<br>60 | Pm<br>61 | Sm<br>62 | Eu<br>63 | Gd<br>64 | Tb<br>65 | Dy<br>66 | Ho<br>67 | Er<br>68  | Tm<br>69  | Yb<br>70  | Lu<br>71  |                     |

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# ED & WD Measuring Principle

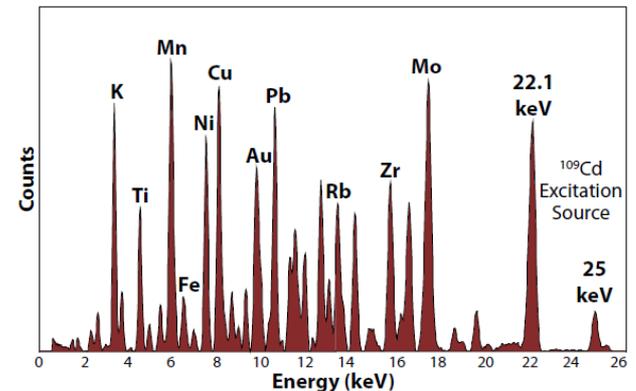


# Amptek Detector

- Compact integrated system
- Used for XRF Instrumentation
- Si-PIN and SDD types used
- 2-stage thermoelectrically cooled
- Energy range 1keV to 40 keV
- Si-PIN resolution 145-260eV FWHM @ 5.9keV
- Si-PIN Maximum count range 200,000 cps
- SDD resolution 125eV FWHM @ 5.9keV
- SDD Maximum count range 100,000 cps



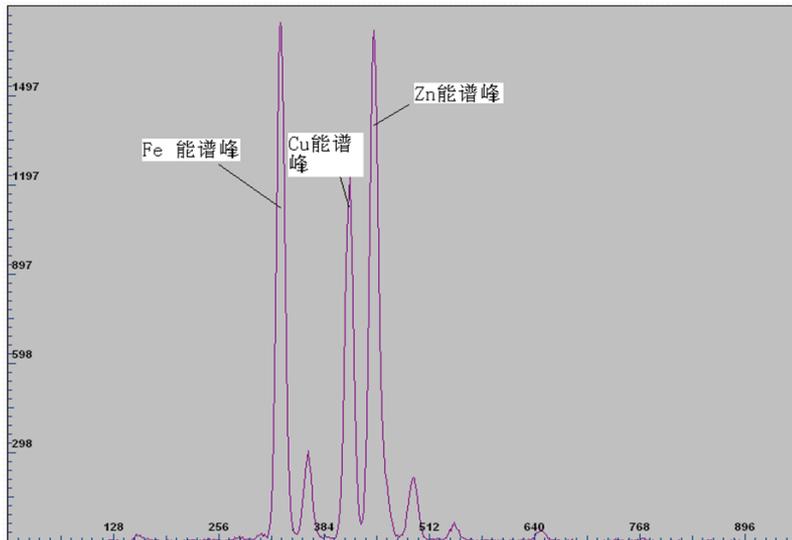
X-Ray Fluorescence from  $^{109}\text{Cd}$



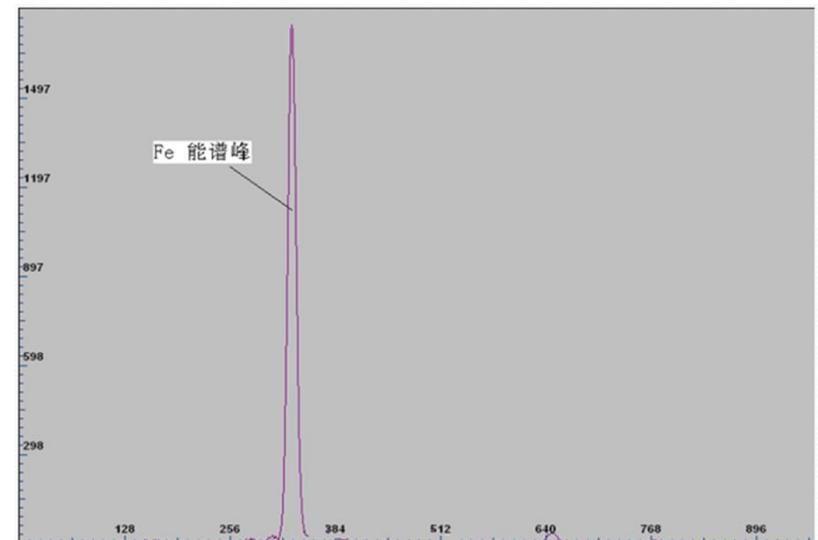
# Spectrum Displays (ED & WD)

- Photons go into a detector and are converted to an electrical pulse, where the amplitude of the pulse is proportional to the photon's energy
- Thousands of pulses produce a spectrum
- Energy dispersive channels have a continuous spectrum of all energies
- Wavelength dispersive channels have a filter to reject unwanted energies

ED Channel

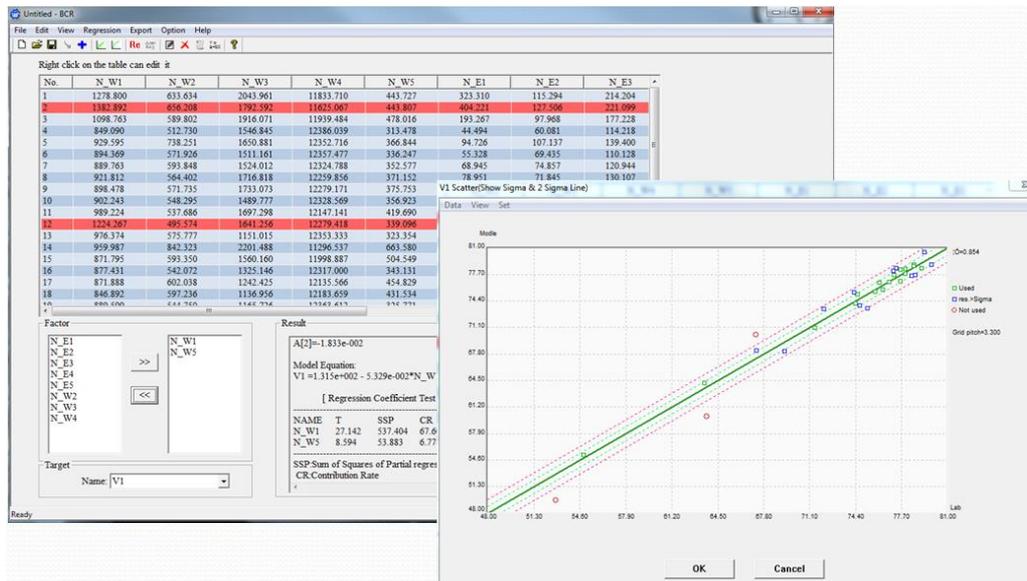


WD Channel



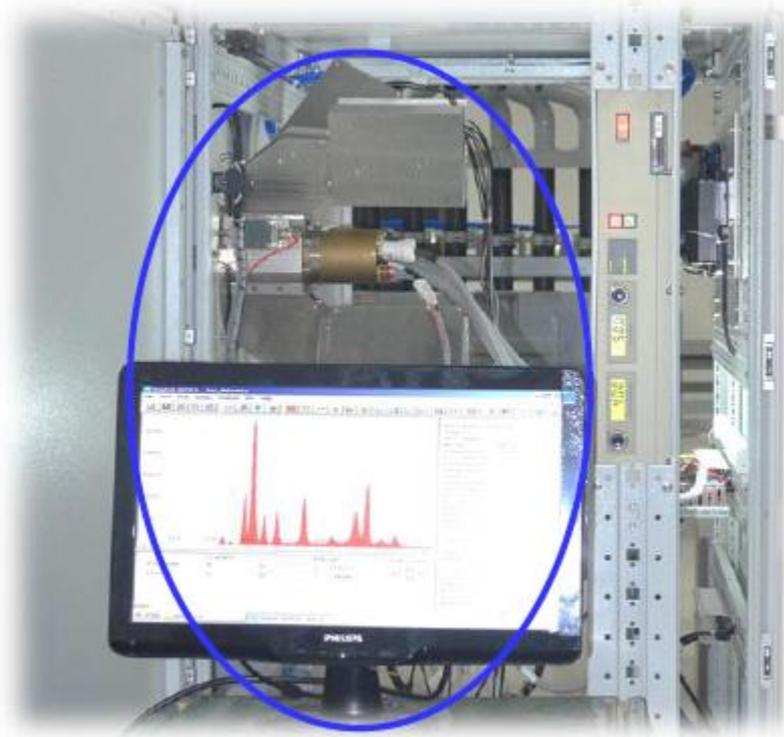
# XRF - Calibration

- From the spectrum results, the count rates (intensities) of each element are calculated. At the same time a sample is taken from the analyzer and assayed by the lab.
- These count rates and lab assays are then used to calculate the element content in the slurry based on a derived formula
  - %Cu= A + B\* Cu Counts
  - %Zn= A + B\* Zn Counts + .....
- Formulas are derived using a regression analysis program



# Channel Sets and X-Ray Tube

## WD and ED Channels

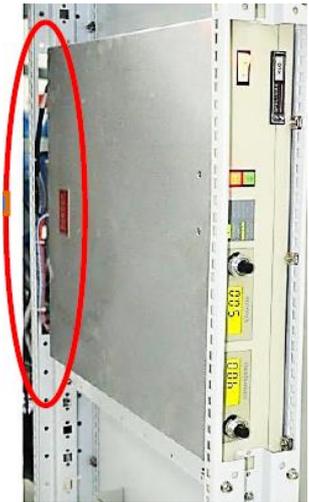
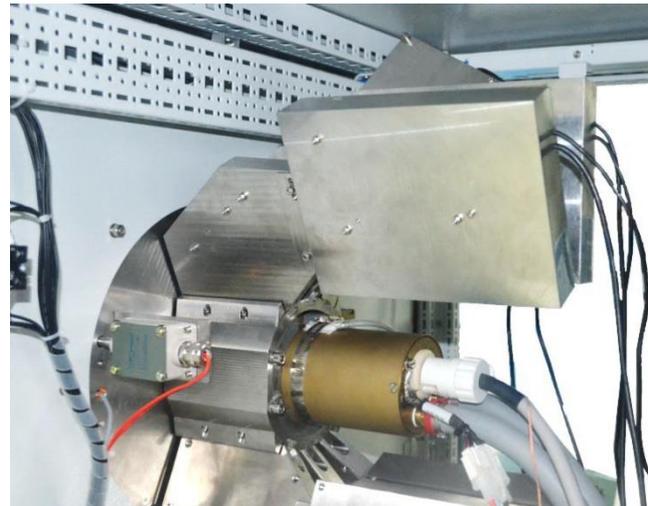


# Dedicated Channel Processor



# Probe Electronics

- Houses XRF excitation and detection electronics, control electronics, calibration sampler and slurry flow cell



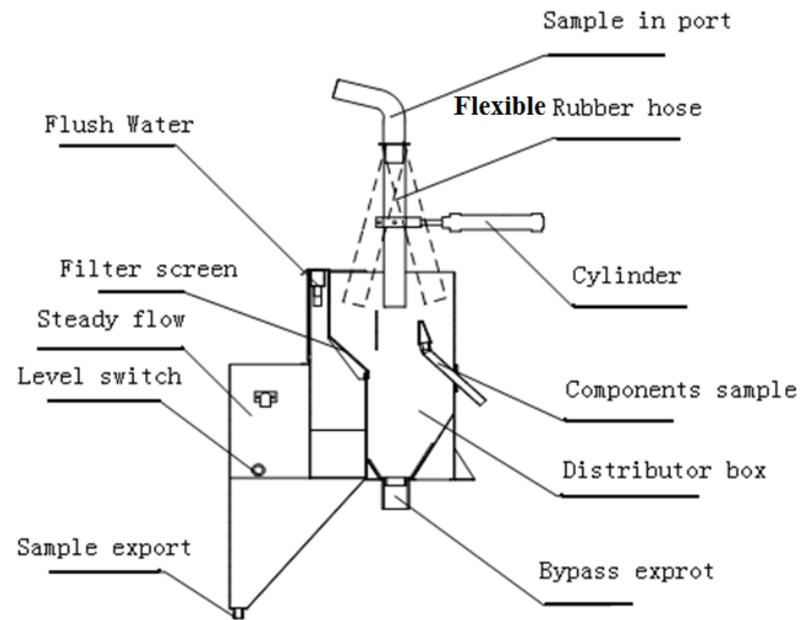
# Probe Control Set

- Houses controllers for MXA's, main controller and a display for operators



# Multiplexers

- Used for sample preparation, de-aeration of sample, and feeding sample to the probe
- MXA and probe flow cell are flushed with water after each sample is measured
- Used for composite / shift samples



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The legend continues

# DCS Modbus – Assay Data

| Address | Data         | Type<br>Floating<br>Decimal<br>(F) |
|---------|--------------|------------------------------------|
| 30001   | MV 1 of SM 1 | F                                  |
| 30002   |              |                                    |
| 30003   | MV 2 of SM 1 | F                                  |
| 30004   |              |                                    |
| 30005   | MV 3 of SM 1 | F                                  |
| 30006   |              |                                    |
| 30007   | MV 4 of SM 1 | F                                  |
| 30008   |              |                                    |
| 30009   | MV 5 of SM 1 | F                                  |
| 30010   |              |                                    |
| 30011   | MV 6 of SM 1 | F                                  |

# DCS Modbus – Assay Data

| Address | Alarm ID | Alarm information                                | type Integer(I) | Value  |          |
|---------|----------|--|-----------------|--------|----------|
|         |          |  |                 | 0      | 1        |
| 31101   | 1        | [1]Caution light for X-ray failure               | I               | normal | abnormal |
| 31102   | 2        | [2]Meas cell open failure                        | I               | normal | abnormal |
| 31103   | 3        | [3]Meas cell close failure                       | I               | normal | abnormal |
| 31104   | 4        | [4]X-ray tube not on the right position          | I               | normal | abnormal |
| 31105   | 5        | [5]X-ray tube inner temperature over upper limit | I               | normal | abnormal |
| 31106   | 6        | [6]Meas cell film broken                         | I               | normal | abnormal |
| 31107   | 7        | [7]Insufficient air pressure                     | I               | normal | abnormal |
| 31108   | 8        | [8]X-ray tube surface temperature too high       | I               | normal | abnormal |
| 31109   | 9        | [9]Analyser temperature too high                 | I               | normal | abnormal |
| 31110   | 10       | [10]X-ray tube current lower than the set value  | I               | normal | abnormal |
| 31111   | 11       | [11]X-ray tube voltage lower than the set value  | I               | normal | abnormal |
| 31112   | 12       | [12]X-ray tube current upper than the set value  | I               | normal | abnormal |
| 31113   | 13       | [13]X-ray tube voltage upper than the set value  | I               | normal | abnormal |



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# Installation Example



Doe Run - Fletcher Mill



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# BOXA Benefits & Advantages

- New construction
  - Majority of critical electronics' parts are from **proven** US suppliers
  - Cabinet is large enough to allow easy access for maintenance, not cramped - **Rittal**
  - Si-PIN / SDD detectors output spectrum to ARK PC, no requirement for separate HV, Pre-amp, and pulse processing – **Amptek (they have a detector on the mars probe)**
  - Reference is outside and mechanism is air driven, easier maintenance, no springs (fatigue), more reliable, no extra openings in x-ray tube housing (radiation and tight tolerances)
  - System is air cooled
  - X-ray tube is oil cooled, oil is air cooled, one unit - **Varian**
  - Database is SQL, open to customer, not proprietary

# BOXA Benefits & Advantages

- 50+ yrs of XRF experience within H&S (Minexan 151, Beltcon 200, Courier 10/20/30/300/30XP/6/6i)
- Economical Investment with comparable quality
- Easy to install, calibrate and maintain
- Reliable system operation
  - stability of measurement cabinet & internal reference
  - improved calibration software BCR<sub>BGRIMM</sub>
  - power regulation - UPS
  - solid construction
  - current hardware & software
- Service & Engineering network to assist with measurement and sampling problems

# Next Generation BOXA-III

- Designed in collaboration between BGRIMM and H&S
- PCS Control panel is removed
- Replaced with adjustable display
- MXA Controls moved into Probe set.
- Digital I/O wiring to MXA's replace by communication line
- Reduces installation foot print
- Redesigned MXA/CSA by H&S



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**The legend continues**

# Benefits of OSA Systems

- Daily reconciliations and balances are accurately calculated (shift composite samples)
- Mass balancing can be done online (requires 3<sup>rd</sup> party software)
- Reagents can be adjusted online to control grade and recovery efficiently. Reagent consumption and their cost is reduced
- Process upsets can be quickly noticed and corrected
- Areas in the plant where losses are occurring can be identified and the required changes made

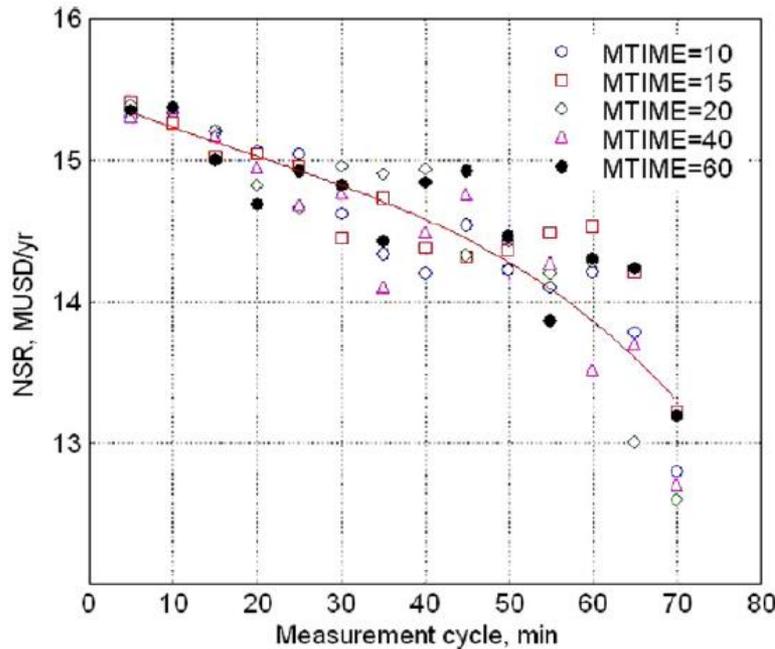
# Benefits of OSA Systems

- Improved process production/recovery and quality/grade.
- Reduce process variability
- Economic optimization
- A small 1% process improvement in a \$100M/yr. (small plant) production plant is \$1M/yr. OSA system and installation is paid for in one year
- Think about \$500M/yr. or more.
- **“Can you really afford not to have an OSA System”**

# Some \$ Numbers

- \$250K reagent savings – Kidd Creek [Thwaites, 1983]
- \$1.5M improved grade and recoveries – Buick [Deister, 1985]
- Non-Optimal control effect of analysis cycle speed, Pyhasalmi Mine [Elsevier article, 2007]

NSR – Net Smelter Return



**With no OSA, measurement delays are in hours or days!!!**



*Thank-you*  
*from*  
**HEATH & SHERWOOD**  
**&**  
**BGRIMM**



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